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In re Patent Application of:

KENNETH JOHN DAVEY

Serial No. **09/848,648**

Filing Date: **May 3, 2001**

For: **SYSTEM AND METHOD FOR THE
DETECTION AND PROPAGATION
MEASUREMENT OF FLAWS IN A
COMPONENT OR STRUCTURE**

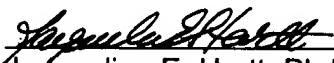
Asst. Commissioner for Patents
Washington, D.C. 20231

Sir:

TRANSMITTAL OF SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

In compliance with 37 C.F.R. §1.97(b), it is respectfully requested that the Information Disclosure Statement (Form PTO/SB/08A) attached hereto be entered and the references listed thereon be considered by the Examiner and made of record. Copies of the listed references are enclosed.

Respectfully submitted,


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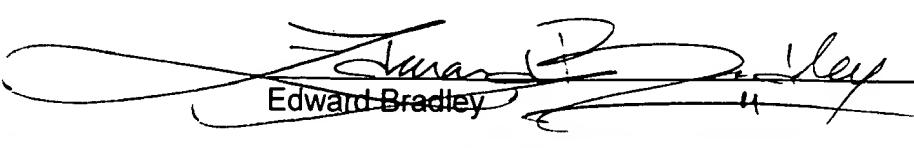
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CERTIFICATE OF MAILING

I hereby certify that the foregoing is being deposited with the United States Postal Service as first class mail in an envelope addressed to the Assistant Commissioner of Patents, Washington D.C. 20231, this 26th day of June, 2002.


Edward Bradley

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